

Notice of References Cited	Application/Control No. 10/581,256		Applicant(s)/Patent Under Reexamination OKUNE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagata et al. (Japanese Journal of Applied Physics, Vol. 28, No. 11, November, 1989, pp. 2368-2371)
	V	Tzeng et al. (J. Electrochem. Soc. Vol. 134, No. 9, September 1987, pp. 2304-2309)
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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